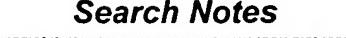


<b>Search Notes</b> 	<b>Application/Control No.</b> 10/533,074	<b>Applicant(s)/Patent under Reexamination</b> JIN, BENYOU
	<b>Examiner</b> Henok Legesse	<b>Art Unit</b> 2809

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner